International Rectifier

IRF9530NPbF

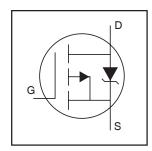
HEXFET® Power MOSFET

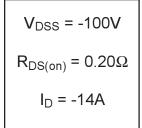
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Lead-Free

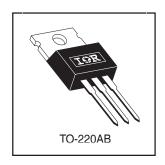
Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







Absolute Maximum Ratings

	•			
	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ -10V	-14		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ -10V	-10	A	
I _{DM}	Pulsed Drain Current ①	-56		
P _D @T _C = 25°C	Power Dissipation	79	W	
	Linear Derating Factor	0.53	W/°C	
V_{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy®	250	mJ	
I _{AR}	Avalanche Current①	-8.4	А	
E _{AR}	Repetitive Avalanche Energy①	7.9	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.9	
R _{θCS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	-100			V	$V_{GS} = 0V, I_D = -250\mu A$
Breakdown Voltage Temp. Coefficient		-0.11		V/°C	Reference to 25°C, I _D = -1mA
Static Drain-to-Source On-Resistance			0.20	Ω	V _{GS} = -10V, I _D = -8.4A ④
Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
Forward Transconductance	3.2			S	$V_{DS} = -50V, I_{D} = -8.4A$
Drain-to-Source Leakage Current			-25		V _{DS} = -100V, V _{GS} = 0V
Drain-to-oddree Leakage Garrent			-250	μΑ [$V_{DS} = -80V$, $V_{GS} = 0V$, $T_{J} = 150$ °C
Gate-to-Source Forward Leakage			100	nΛ	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-100	114	V _{GS} = -20V
Total Gate Charge			58		I _D = -8.4A
Gate-to-Source Charge			8.3	nC	$V_{DS} = -80V$
Gate-to-Drain ("Miller") Charge			32		V_{GS} = -10V, See Fig. 6 and 13 \oplus
Turn-On Delay Time		15			V _{DD} = -50V
Rise Time		58			$I_D = -8.4A$
Turn-Off Delay Time		45		ns	$R_G = 9.1\Omega$
Fall Time		46			R_D = 6.2 Ω , See Fig. 10 \oplus
Internal Drain Inductance		45			Between lead,
Therial Dialit inductance —— 4.3 —	nl	nH	6mm (0.25in.)		
Internal Source Inductance		7.5			from package
					and center of die contact
Input Capacitance		760			V _{GS} = 0V
Output Capacitance		260		pF	$V_{DS} = -25V$
Reverse Transfer Capacitance		170			f = 1.0MHz, See Fig. 5
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Source Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Input Capacitance Output Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage -100 — Breakdown Voltage Temp. Coefficient — -0.11 Static Drain-to-Source On-Resistance — — Gate Threshold Voltage -2.0 — Forward Transconductance 3.2 — Drain-to-Source Leakage Current — — Gate-to-Source Forward Leakage — — Gate-to-Source Reverse Leakage — — Total Gate Charge — — Gate-to-Source Charge — — Gate-to-Drain ("Miller") Charge — — Turn-On Delay Time — 15 Rise Time — 45 Fall Time — 46 Internal Drain Inductance — 7.5 Internal Source Inductance — 7.5 Input Capacitance — 760 Output Capacitance — 260	Drain-to-Source Breakdown Voltage -100 — — Breakdown Voltage Temp. Coefficient — -0.11 — Static Drain-to-Source On-Resistance — -0.20 Gate Threshold Voltage -2.0 — -4.0 Forward Transconductance 3.2 — — Drain-to-Source Leakage Current — -25 — -25 Gate-to-Source Forward Leakage — - -250 Gate-to-Source Reverse Leakage — - -100 Total Gate Charge — - 58 Gate-to-Source Charge — 8.3 Gate-to-Drain ("Miller") Charge — 32 Turn-On Delay Time — 15 — Rise Time — 58 — Turn-Off Delay Time — 45 — Fall Time — 46 — Internal Drain Inductance — 7.5 — Input Capacitance — 760 — Output Capacita	Drain-to-Source Breakdown Voltage -100 — — V Breakdown Voltage Temp. Coefficient — -0.11 — V°C Static Drain-to-Source On-Resistance — — 0.20 Ω Gate Threshold Voltage -2.0 — -4.0 V Forward Transconductance 3.2 — — S Drain-to-Source Leakage Current — -25 — S Gate-to-Source Forward Leakage — — -250 µA Gate-to-Source Reverse Leakage — — -100 nA Gate-to-Source Charge — — -58 nC Gate-to-Drain ("Miller") Charge — 32 nC Gate-to-Drain ("Miller") Charge — 32 n Turn-On Delay Time — 58 — Rise Time — 45 — Fall Time — 46 — Internal Drain Inductance — 7.5 — Input Capacitan

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			-14		MOSFET symbol
	(Body Diode)		-14	A	showing the	
I _{SM}	Pulsed Source Current			EG		integral reverse
	(Body Diode) ①		56	'	p-n junction diode.	
V _{SD}	Diode Forward Voltage			-1.6	V	T _J = 25°C, I _S = -8.4A, V _{GS} = 0V ⊕
t _{rr}	Reverse Recovery Time		130	190	ns	$T_J = 25^{\circ}C, I_F = -8.4A$
Q _{rr}	Reverse RecoveryCharge		650	970	nC	di/dt = -100A/μs ⊕
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting T_J = 25°C, L = 7.0mH R_G = 25 Ω , I_{AS} = -8.4A. (See Figure 12)
- $\begin{tabular}{ll} \begin{tabular}{ll} \be$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.

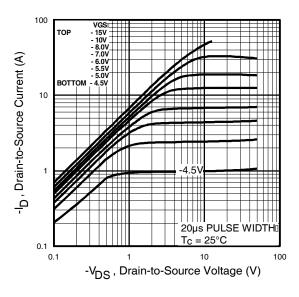


Fig 1. Typical Output Characteristics

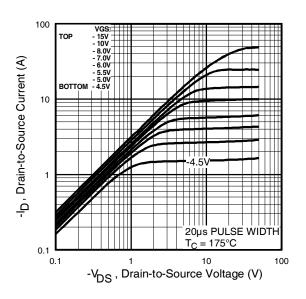


Fig 2. Typical Output Characteristics

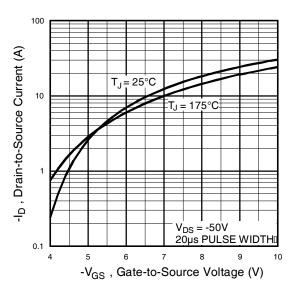


Fig 3. Typical Transfer Characteristics

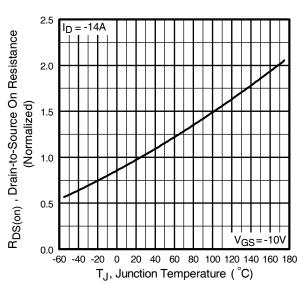


Fig 4. Normalized On-Resistance Vs. Temperature

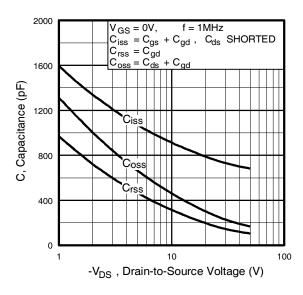


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

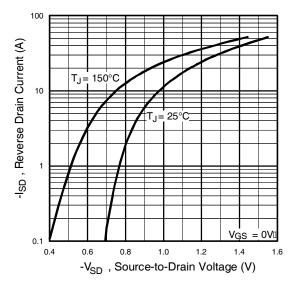


Fig 7. Typical Source-Drain Diode Forward Voltage

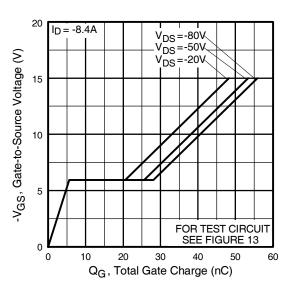


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

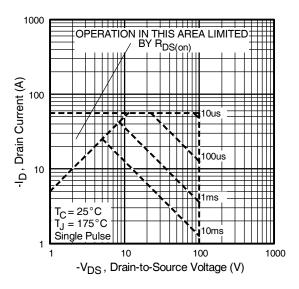


Fig 8. Maximum Safe Operating Area

International TOR Rectifier

IRF9530NPbF

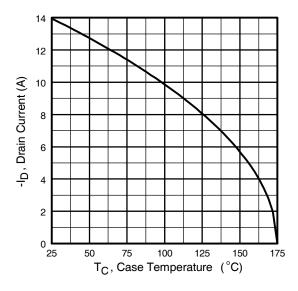


Fig 9. Maximum Drain Current Vs.
Case Temperature

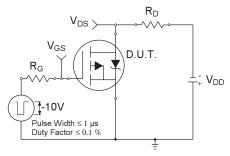


Fig 10a. Switching Time Test Circuit

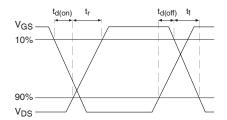


Fig 10b. Switching Time Waveforms

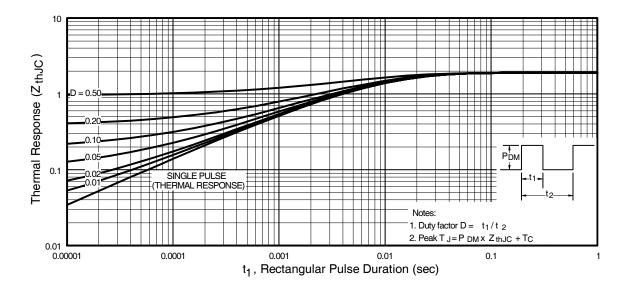


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

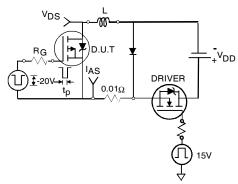


Fig 12a. Unclamped Inductive Test Circuit

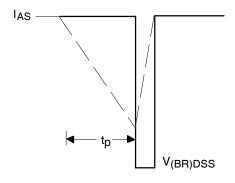


Fig 12b. Unclamped Inductive Waveforms

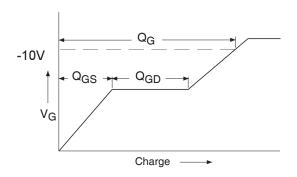


Fig 13a. Basic Gate Charge Waveform

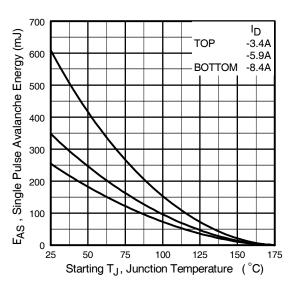


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

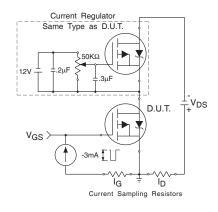
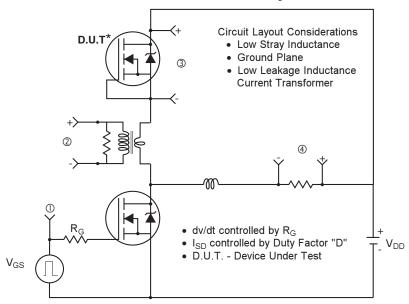


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



^{*} Reverse Polarity of D.U.T for P-Channel

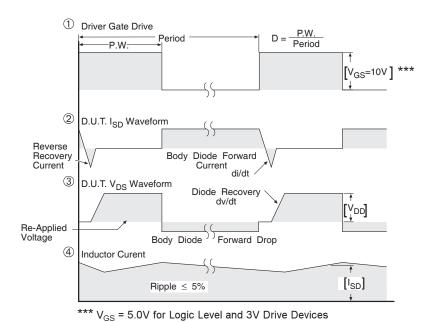
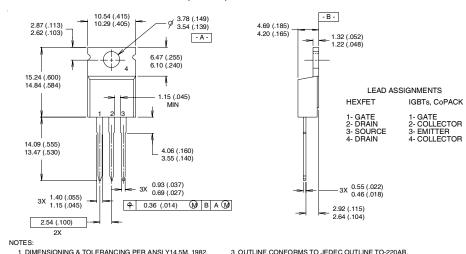


Fig 14. For P-Channel HEXFETS

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)

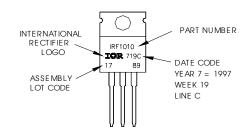


2 CONTROLLING DIMENSION: INCH

4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"
Note: "P" in assembly line
position indicates "Lead-Free"



Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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